EXAMINER'S AMENDMENT

1.   An examiner's amendment to the record appears below. Should the changes

and/or additions be unacceptable to applicant, an amendment may be filed as provided

by 37 CFR 1.312. To ensure consideration of such an amendment, it MUST be

submitted no later than the payment of the issue fee.

The application has been amended as follows:

Claim 102, line 18, change "data." to --data;--.

Remarks: the above corrects an obvious typographical error by changing a

period to a semicolon.

2.   A request for continued examination under 37 CFR 1.114, including the fee set

forth in 37 CFR 1.17(e), was filed in this application after final rejection. Since this

application is eligible for continued examination under 37 CFR 1.114, and the fee set

forth in 37 CFR 1.17(e) has been timely paid, the finality of the previous Office action

has been withdrawn pursuant to 37 CFR 1.114. Applicant's submission filed on 1/2/08

has been entered.

3.   In view of the express abandonment of the 11/458,637 application the

provisional obviousness type double patenting rejection on the basis of the 11/45,637

application is withdrawn.

4.   The following is an examiner's statement of reasons for allowance: Pasadyn et

al. 2004/0029299 and Funk 2005/0165731 are the closest art of record.

5.   Regarding claim 1 and its dependent claims 2-5,7, 8, the prior art does not teach

or suggest in the claimed method collecting non-production data by taking at least one

measurement related to an entire manufacturing facility where the electronic device

manufacturing process resides and not directly related to the electronic device

manufacturing process; performing calculations on the production data including

weighting the production data based on distance between a sampling point for the

production data and a process location; performing calculations on the non-production

data including weighting the non-production data based on distance between a

sampling point for the non-production data and a process location; keying the

production data; keying the non-production data; combining the production data and the

non-production data into a single data set; storing the single data set on a computer

memory; and analyzing said single data-set to determine conditions in the electronic

device manufacturing process.

6.   Regarding claim 9 and its dependent claims 10,12-15, the prior art does not

teach or suggest in the claimed method collecting non-production data from a single

data source from at least one of a plurality of locations with some temporal periodicity

by taking at least one measurement related to an entire manufacturing facility where the

electronic device manufacturing process resides and not directly related to the

electronic device manufacturing process; performing calculations on the production data

including weighting the production data based on distance between a sampling point for

the production data and a process location; performing calculations on the non-

production data including weighting the non- production data based on distance between a sampling point for the non-production data and a process location;

keying the production data; keying the non-production data; combining the production data and the non-production data into a single data set; storing the single data set on a computer memory; and analyzing said single data-set to determine conditions in the electronic device manufacturing process.

Regarding claim 17 and its dependent claim 18, the prior art does not teach or suggest in the claimed method collecting non-production data by taking at least one measurement related to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process; performing calculations on the production data; performing weighted mean calculations on the non-production data; keying the production data; keying the non-production data; combining the production data and the non-production data into a single data set; storing the single data set on a computer memory; and analyzing said single data-set to determine conditions in the electronic device manufacturing process.

7.   Regarding claim 23 and its dependent claims 24-25, the prior art does not teach or suggest in the claimed method collecting non-production data by taking at least one measurement related to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process; performing calculations on the production data; performing weighted mean calculations on the non-production data;

keying the production data; keying the non-production data; identifying points of data commonality between the production and non-production data set; defining relationships based on the identified commonalities; combining the production data and the non-production data based on the defined relationships into a single data-set; storing the single data-set on a computer memory; and analyzing said single data-set to determine conditions in the electronic device manufacturing process.

8.   Regarding claim 26 and its dependent claims 27-30,32,33, the prior art does not teach or suggest in the claimed method collecting non-production data by taking at least one measurement related to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process; performing calculations on the production data including weighting the production data based on distance between a sampling point for the production data and a process location; performing calculations on the non-production data including weighting the non- production data based on distance between a sampling point for the non-production data and a process location; keying production data; keying non-production data; combining the production data and the non-production data into a single data set; storing the single data set on a computer memory; analyzing said data set; and examining the analysis of the data for conditions of the electronic device manufacturing process.

9.   Regarding claim 34 and its dependent claims 35,37-40, the prior art does not teach or suggest in the claimed method collecting non-production data from a single data source with some temporal periodicity by taking at least one measurement related

to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process; performing calculations on the production data including weighting the production data based on distance between a sampling point for the production data and a process location; performing calculations on the non-production data including weighting~ the non- production data based on distance between a sampling point for the non-production data and a process location; keying the production data; keying the non-production data; combining the production data and the non-production data into a single data set; storing the single data set on a computer memory; analyzing the single data set; and examining the analysis of the data for conditions of the electronic device manufacturing process.

10.   Regarding claim 42 and its dependent claims 43,46,47, the prior art does not teach or suggest in the claimed method collecting non-production data by taking at least one measurement related to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process; performing calculations on the production data; performing weighted mean calculations on the non-production data; keying the production data; keying the non-production data; combining the production data and the non-production data into a single data set; storing the single data set on a computer memory; analyzing the single data set; and examining the analysis of the data for conditions of the electronic device manufacturing process.

11.   Regarding claim 48 and its dependent claims 49-54, the prior art does not teach

or suggest in the claimed method collecting non-production data by taking at least one

measurement related to an entire manufacturing facility where the electronic device

manufacturing process resides and not directly related to the electronic device

manufacturing process; performing calculations on the production data;

performing weighted mean calculations on the non-production data; keying the

production data; keying the non-production data; identifying points of data commonality

between the production and non-production data set; defining relationships based on

the identified commonalities; combining the production data and the non-production

data based on the defined relationships into a single data-set; storing the single data-

set on a computer memory; analyzing the single data-set; and examining the analysis

of the data for conditions of the electronic device manufacturing process.

12.   Regarding claim 55 and its dependent claims 56-60, the prior art does not teach

or suggest in the claimed method collecting non-production data by taking at least one

measurement related to an entire manufacturing facility where the electronic device

manufacturing process resides and not directly related to the electronic device

manufacturing process; performing calculations on the production data, wherein the

measurements of the production data are taken over time and wherein the production

data is weighted based on a time value; performing weighted mean calculations on the

non-production data; keying the production data; keying the non-production data;

identifying points of data commonality between the production and non-production data

set; defining relationships based on the identified commonalities; combining the production data and the non-production data based on the defined relationships into a single data-set; storing the single data-set on a computer memory; analyzing the single data-set; and examining the analysis of the data for conditions of the electronic device manufacturing process.

13.   Regarding claim 61 and its dependent claims 62-68, the prior art does not teach or suggest in the claimed combination collecting non-production data by taking at least one measurement related to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process; performing calculations on the production data including weighting the non- production data based on distance between a sampling point for the non-production data and a process location; performing calculations on the non-production data including, weighting the non- production data based on distance between a sampling point for the non-production data and a process location;

keying production data; keying non-production data; combining the production data and the non-production data into a single data set; analyzing said data set; and examining the analysis of the data.

14.   Regarding claim 69 and its dependent claims 70,72-76, the prior art does not teach or suggest in the claimed combination collecting non-production data from a single data source with some temporal periodicity by taking at least one measurement related to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process;

performing calculations on the production data including weighting the non-production data based on distance between a sampling point for the non-production data and a process location; performing calculations on the non-production data including weighting the non-production data based on distance between a sampling point for the non-production data and a process location; keying the production data; keying the non-production data; combining the production data and the non-production data into a single data set; analyzing the single data set; and examining the analysis of the data.

15.   Regarding claim 77 and its dependent claims 78,81,82, the prior art does not teach or suggest in the claimed combination collecting non-production data from a single data source with some temporal periodicity by taking at least one measurement related to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process;

performing calculations on the production data; performing weighted mean calculations on the non-production data; keying the production data; keying the non-production data; combining the production data and the non-production data into a single data set; analyzing the single data set; and examining the analysis of the data.

16.   Regarding claim 83 and its dependent claims 84-88, the prior art does not teach or suggest in the claimed combination collecting non-production data by taking at least one measurement related to an entire manufacturing facility where the electronic device manufacturing process resides and not directly related to the electronic device manufacturing process; performing calculations on the production data; performing

weighted mean calculations on the non-production data; keying the production data;

keying the non-production data; identifying points of data commonality between the

production and non- production data set; defining relationships based on the identified

commonalities; combining the production data and the non-production data based on

the defined relationships into a single data-set; analyzing the single data-set; and

examining the analysis of the data.

17.   Regarding claim 89 and its dependent claims 90-94, the prior art does not teach

or suggest in the claimed combination collecting non-production data by taking at least

one measurement related to an entire manufacturing facility where the electronic device

manufacturing process resides and not directly related to the electronic device

manufacturing process; performing calculations on the production data;

performing weighted mean calculations on the non-production data; keying the

production data; keying the non-production data; identifying points of data commonality

between the production and non- production data set; defining relationships based on

the identified commonalities; combining the production data and the non-production

data based on the defined relationships into a single data-set; analyzing a single data-

set stored remotely on a server; and examining the analysis of the data.

18.   Regarding claim 95 and its dependent claims 96-101, the prior art does not

teach or suggest in the claimed combination collecting non-production data by taking at

least one measurement related to an entire manufacturing facility where the electronic

device manufacturing process resides and not directly related to the electronic device

manufacturing process; performing calculations on the production data, wherein the

measurements of the production data are taken over time and wherein the production

data is weighted based on a time value; performing calculations on the non-production

data including weighting the non- production data based on distance between a

sampling point for the non-production data and a process location; keying production

data; keying non-production data; combining the production data and the non-

production data into a single data set; analyzing said data set.

19.   Regarding claim 102 and its dependent claims 103-105, the prior art does not

teach or suggest in the claimed method collecting non-production data from the of

plurality of data sources separated by some non-fixed distance from a manufacturing

process by taking at least one measurement related to an entire manufacturing facility

where the electronic device manufacturing process resides and not directly related to

the electronic device manufacturing process; performing calculations on the production

data; performing weighted mean calculations on the non-production data, weighted by

time, distance or distance/time; keying production data by adding the of a plurality of

calculated production data to the production data from the production lots that were

processed during the collection of the non- production data; combining the production

data and the non-production data into a single data set; analyzing said data set; and

examining the analysis of the data combining the production data and the non-

production data based on the defined

relationships into a single data-set;

analyzing the single data-set by trend or statistical analysis;

Any comments considered necessary by applicant must be submitted no later than the payment of the issue fee and, to avoid processing delays, should preferably accompany the issue fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for Allowance."

20.   Any inquiry concerning this communication or earlier communications from the examiner should be directed to STEVEN R. GARLAND whose telephone number is (571)272-3741. The examiner can normally be reached on Monday-Friday.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Albert Decady can be reached on 571-272-3997. The fax phone number for the organization where this application or proceeding is assigned is 571-273-8300.

Information regarding the status of an application may be obtained from the Patent Application Information Retrieval (PAIR) system. Status information for published applications may be obtained from either Private PAIR or Public PAIR. Status information for unpublished applications is available through Private PAIR only. For more information about the PAIR system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free). If you would like assistance from a USPTO Customer Service Representative or access to the automated information system, call 800-786-9199 (IN USA OR CANADA) or 571-272-1000.

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Steven R Garland
Examiner
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